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INEC	DMATION I			Application Number	09/620,968
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SIA				First Named Inventor	Shunpei YAMAZAKI
				Art Unit	2814
				Examiner Name	Nathan Ha
Sheet	1	of	11	Attorney Docket Number	740756-2183

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Examiner Initials	Cite No.1	U.S. Patent Document	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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<sup>&</sup>lt;sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at <a href="https://www.uspto.gov">www.uspto.gov</a> or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

<sup>&</sup>lt;sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.



Serial No. 09 620,968 U.S. Department of Commercia ity Docket 0756-2183 Form PTO-1449 Patent and Trademark Office (Rev 8-83) Applicants: Shunpei YAMAZAKI INFORMATION DISCLOSURE STATEMENT Group Art Unit: 2818 Filing Date: July 20, 2000 SEP 0 9 222 FOREIGN PATENT DOCUMENTS Translation Yes No Subclass Class Country Date Document Number Full Eng EP 03/10/1982 0 046 868 Eng Abst 05/11/1989 JP 01-119055 Eng Abst JΡ 02/28/1990 02-060157 Eng Abst 03/15/1990 JΡ 02-076257 Eng Abst JP 05/24/1990 02-135777 Eng Abst 03/16/1982 jр 57-045968 Date Considered

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Serial No. Not Yet Assigned Form PTO-1449 U.S. Department of Commerce Attorney Docket No. 0756-2183 Patent and Trademark Office (Rev. 8-83) Applicant: Shunpei YAMAZAKI INFORMATION DISCLOSURE STATEMENT 2 0 2003 Filing Date: July 20, 2000 Group: 2811 (Use several sheets if necessary) **U.S. PATENT DOCUMENTS** Filing Date (if Class Subclass Name **Document Number** Date Examiner appropriate) Initial 5.047.359 09/10/91 Nagatomo 5,047,812 10/10/91 **Pfiester** 10/01/91 Kojima 5.053.842 10/08/91 5,056,010 Huang 02/04/92 Kimura 5,086,010 2/23/93 Suguro 5,189,503 5,136,534 08/04/92 McDavid et al. FOREIGN PATENT DOCUMENTS Class **Subclass** Translation\_ Date Country **Document Number** Yes No Full 08/19/81 **United Kingdom** 2 103 879A M 03/23/89 **PCT** Full WO 89/02655 **Abstract** JP 01-171275 7/6/89 Japan Abstract 1/31/87 JP 62-23117 Japan **Abstract** 12/25/87 Japan JP 62-298119 **Abstract** JP 02-47256 2/16/90 Japan **Abstract** JP 03-16129 24/1/91 Japan Abstract JP 03-79028 4/4/91 Japan Full EP 445535 11/9/91 European Full 03/01/90 European EP 349187 X 8/16/89 Japan 1-203666 X 62-269363 11/21/87 Japan X 63-199456 8/17/88 Japan X 1-248557 10/4/89 Japan ЦD 2-79475 3/20/90 Japan 4/28/04 **Date Considered** Examiner \*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not consider d. Includ copy of this form with next communication to applicant.

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INFO	RMATION DISCLOSURE STA	Applicant: Shunpei YAMAZAKI						
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